# MSKSEMI 美森科













ESD

TVS

TSS

MOV

GDT

PIFD

AZ5325-01F.R7G

**Product specification** 





#### **Features**

- ●80W peak pulse power per line (t<sub>P</sub> = 8/20µs)
- ●DFN1006-2L package
- Replacement for MLV(0402)
- Bidirectional configurations
- ●Response time is typically < 1ns
- Low clamping voltage
- ●RoHS compliant
- ●Transient protection for data lines to IEC61000-4-2(ESD) ±25KV(air), ±25KV(contact); IEC61000-4-4 (EFT) 40A (5/50ns)

## **Applications**

- Cellular phones audio
- MP3 players
- Digital cameras
- Portable applicationss
- mobile telephone

## **Mechanical Characteristics**

- Mounting position: Any
- Qualified max reflow temperature:260 °C
- Device meets MSL 1 requirements
- DFN1006-2L without plating

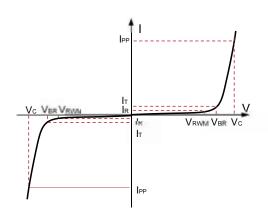
## **Reference News**

PACKAGE OUTLINE	Circuit Diagram	Marking
		1
DFN1006-2L		



## **Electronics Parameter**

Symbol	Parameter		
Vrwm	Peak Reverse Working Voltage		
<b>I</b> R	Reverse Leakage Current @ VRWM		
V <sub>BR</sub>	Breakdown Voltage @ I⊤		
lτ	Test Current		
<b>I</b> PP	Maximum Reverse Peak Pulse Current		
Vc	Clamping Voltage @ IPP		
P <sub>PP</sub>	Peak Pulse Power		
Cı	Junction Capacitance		
lF	Forward Current		
VF	Forward Voltage @ I <sub>F</sub>		



# Electrical characteristics per line@25℃ (unless otherwise specified)

Parameter	Symbol	Conditions	Min.	Тур.	Max.	Units
Peak Reverse Working Voltage	VRWM			5		V
Breakdown Voltage	VBR	k = 1mA	5.6			V
Reverse Leakage Current	<b>I</b> R	V <sub>RWM</sub> = 5V T=25°C			1.0	μA
Clamping Voltage	VcL	IPP= 16A tp= 100ns		24		V
Clamping Voltage	Vc	IPP=1.0A		10	13	V
Clamping Voltage	Vc	IPP=4.5A		18	22	V
Junction Capacitance	Cj	V <sub>R</sub> =0V f = 1MHz		0.25	0.45	pF

# Absolute maximum rating@25℃

Rating	Symbol	Value	Units
Peak Pulse Power (t <sub>p</sub> =8/20µs)	Ppp	80	W
Operating Temperature	TJ	-55 to 150	℃
Storage Temperature	Тѕтс	-55 to 150	℃



## **TypicalCharacteristics**

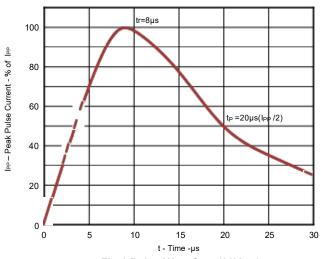


Fig 1.Pulse Waveform(8/20µs)

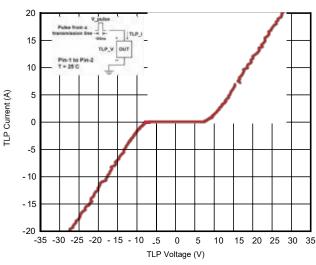


Fig 3. TLP Measurement

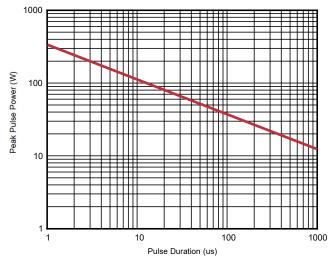


Fig 5. Non Repetitive Peak Pulse Power vs. Pulse time

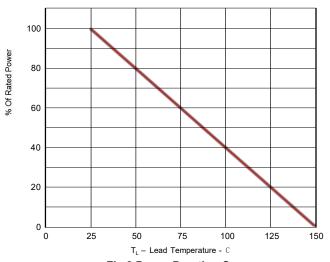


Fig 2.Power Derating Curve

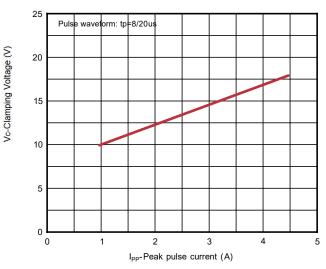
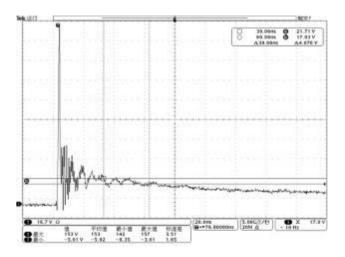


Fig 4. Clamping voltage vs. Peak pulse current





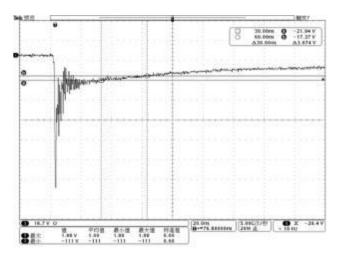
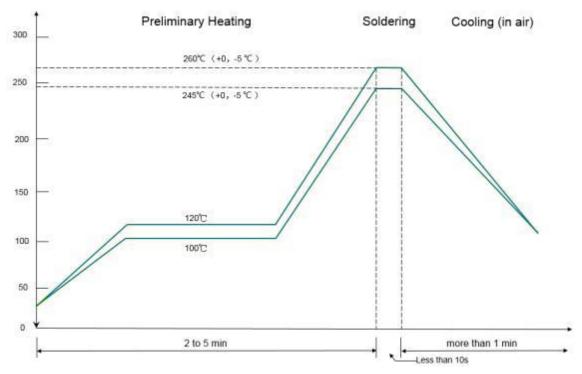


Fig 6.ESD Clamp[ing Voltage] (IEC61000-4-2 +8KV contact)

Fig 7.ESD Clamp[ing Voltage] (IEC61000-4-2 -8KV contact)

#### **Solder Reflow Recommendation**



RRemark: Pb free for 260°C; Pb for 245°C.

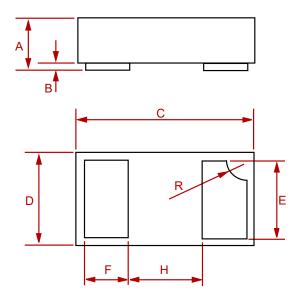
#### PCB Design

For TVS diodes a low-ohmic and low-inductive path to chassis earth is absolutely mandatory in order to achieve good ESD protection. Novices in the area of ESD protection should take following suggestions to heart:

- Do not use stubs, but place the cathode of the TVS diode directly on the signal trace.
- Do not make false economies and save copper for the ground connection.
- Place via holes to ground as close as possible to the anode of the TVS diode.
- Use as many via holes as possible for the ground connection.
- Keep the length of via holes in mind! The longer the more inductance they will have.

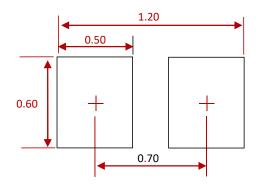


## **PACKAGE MECHANICAL DATA**



Dim	Inches		Millimeters		
Dim	MIN	MAX	MIN	MAX	
А	0.0125	0.02	0.32	0.52	
В	0.000	0.002	0.00	0.05	
С	0.037	0.043	0.95	1.080	
D	0.022	0.027	0.55	0.680	
Е	0.016	0.024	0.40	0.60	
F	0.008	0.012	0.20	0.30	
Н	0.015Typ.		0.40	Тур.	
R	0.001	0.005	0.05	0.15	

## **Suggested Pad Layout**



#### NOTES:

- 1. CONTROLLING DIMENSIONS ARE IN MILLIMETERS (ANGLES IN DEGREES).
- 2. THIS LAND PATTERN IS FOR REFERENCE PURPOSES ONLY. CONSULT YOUR MANUFACTURING GROUP TO ENSURE YOUR COMPANY'S MANUFACTURING GUIDELINES ARE MET.

## **REEL SPECIFICATION**

P/N	PKG	QTY
AZ5325-01F.R7G	DFN1006-2L	10000



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